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sense and simplicity

Digital Silicon Photomultiplier

System Architecture and Performance Evaluation

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Rik de Gruyter

Philips Digital Photon Counting

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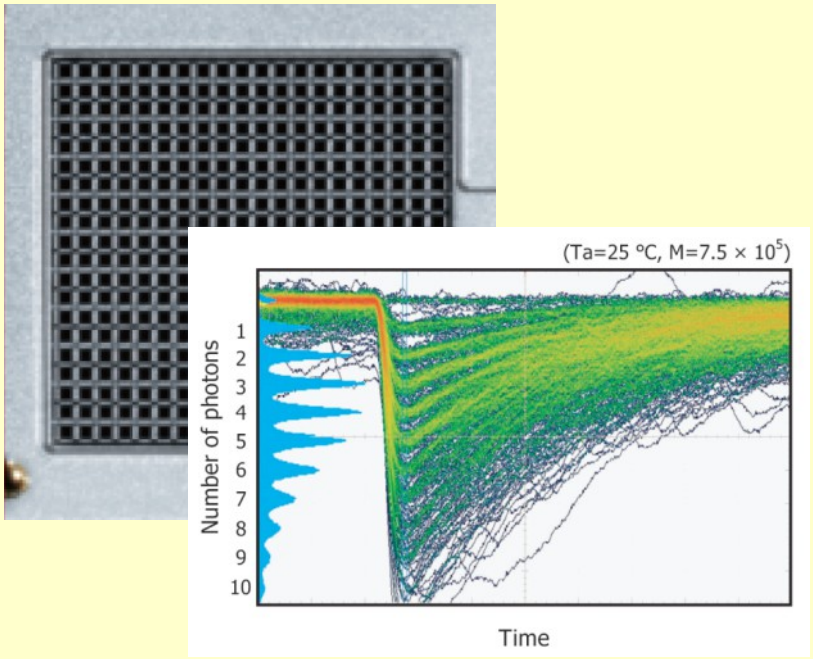
Digital SiPM – New Type of Silicon Photomultiplier

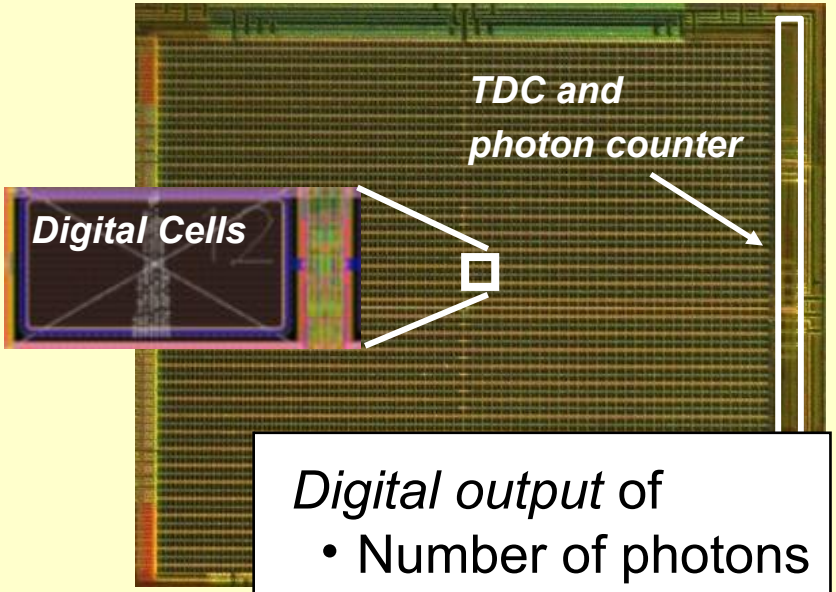
Analog SiPM



www.hamamatsu.com

- Cells connected to common readout
- Analog sum of charge pulses
- Analog output signal

Digital SiPM



Digital output of
- Number of photons
- Time-stamp

- Each diode is a digital switch
- Digital sum of detected photons
- Digital data output

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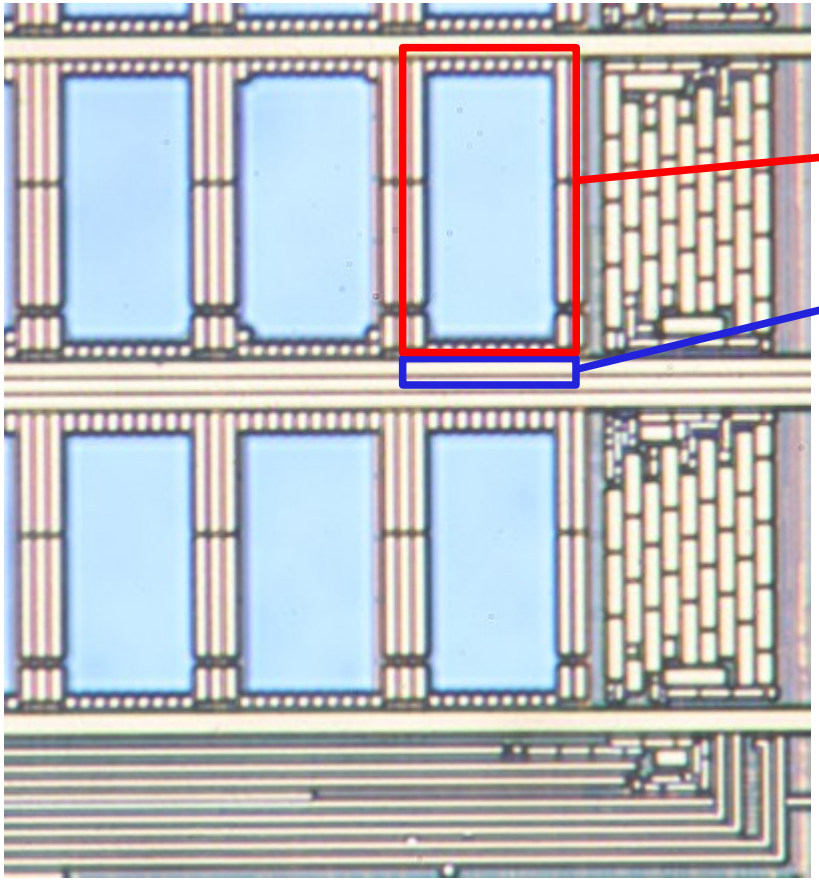
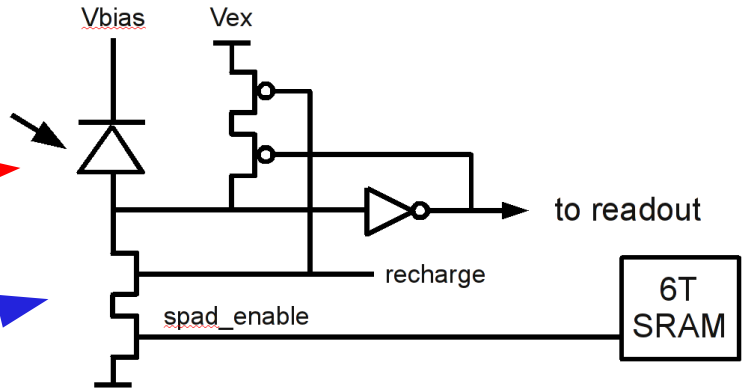
Digital SiPM – Cell Electronics

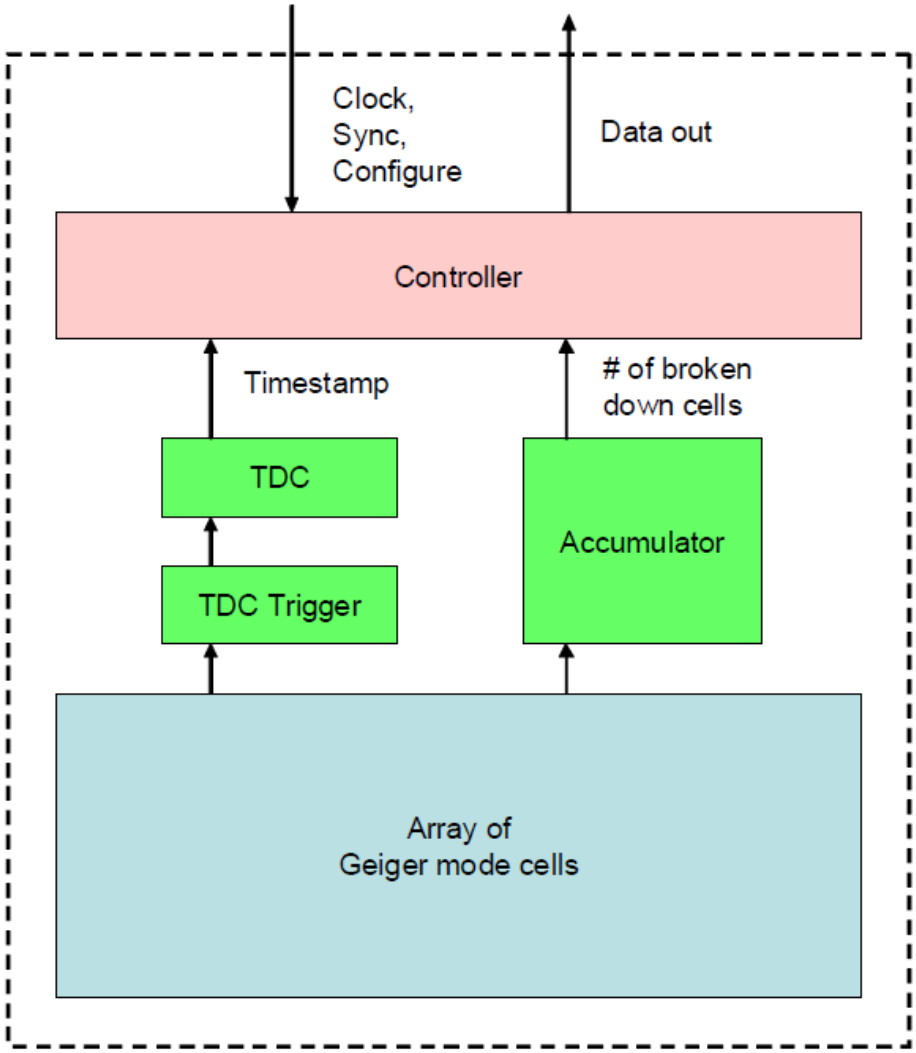




- Cell electronics area: 120μm²
- 25 transistors including 6T SRAM
- ~6% of total cell area
- Modified 0.18μm 5M CMOS
- Foundry: NXP Nijmegen

Digital SiPM – Sensor Architecture

- Operating frequency: 200MHz
- 2 x TDC (bin width 23ps, 9bit)
- Configurable trigger network
- Validation logic to reduce sensor dead time due to dark counts
- JTAG for configuration and scan test
- Electrical trigger input for test and TDC calibration



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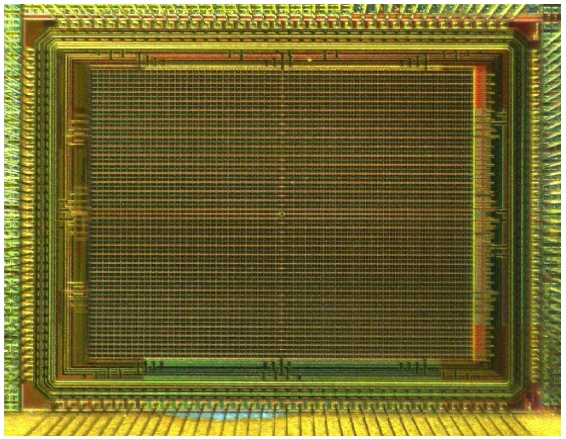
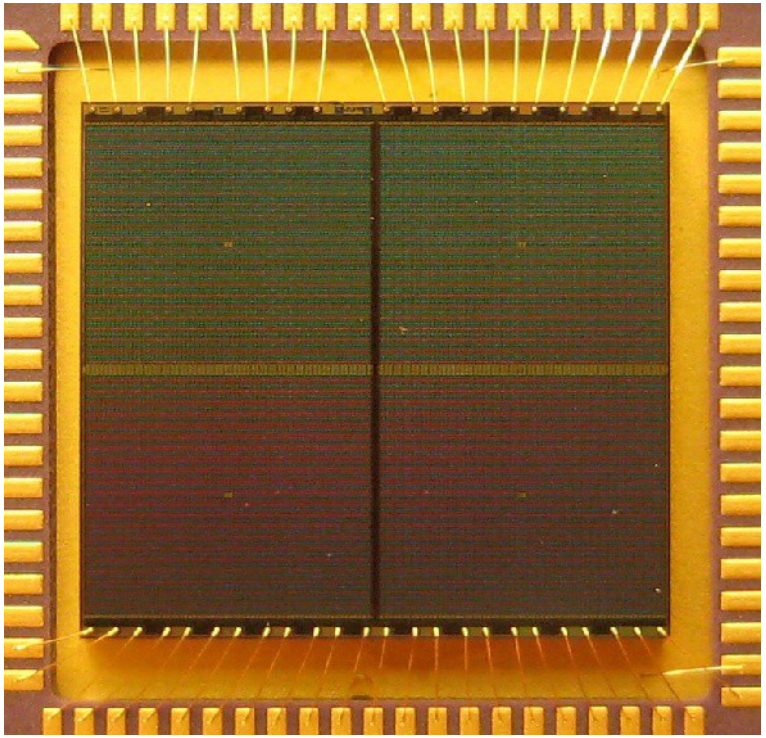
Digital SiPM – Sensor Family

DLD8K Demonstrator (2009):



- 8192 cells
- Integrated TDC
- On-chip inhibit memory controller
- External FPGA controller
- 160 bond wires

DLS 6400-22 digital SiPM (2010):



- 25600 cells
- 2 TDCs, controller, data buffers
- JTAG for configuration & test
- 48 bond wires

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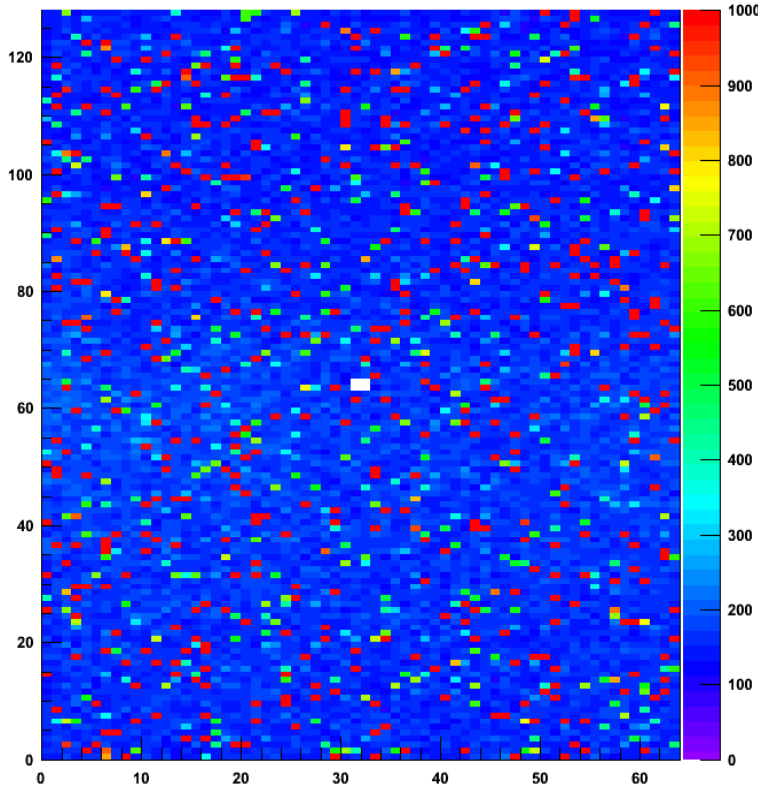
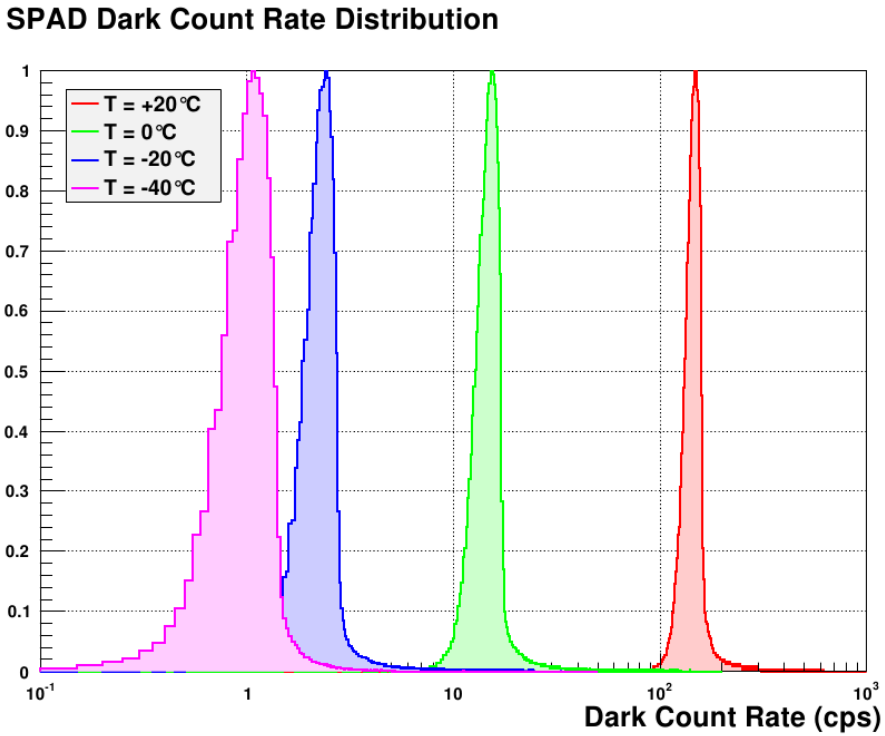
Digital SiPM – Dark Counts

Control over individual SPADs enables detailed device characterization





- Over 90% good diodes (dark count rate close to average)
- Typical dark count rate at 20°C and 3.3V excess voltage: ~150cps / diode
- Low dark counts (~1-2cps) per diode at -40°C

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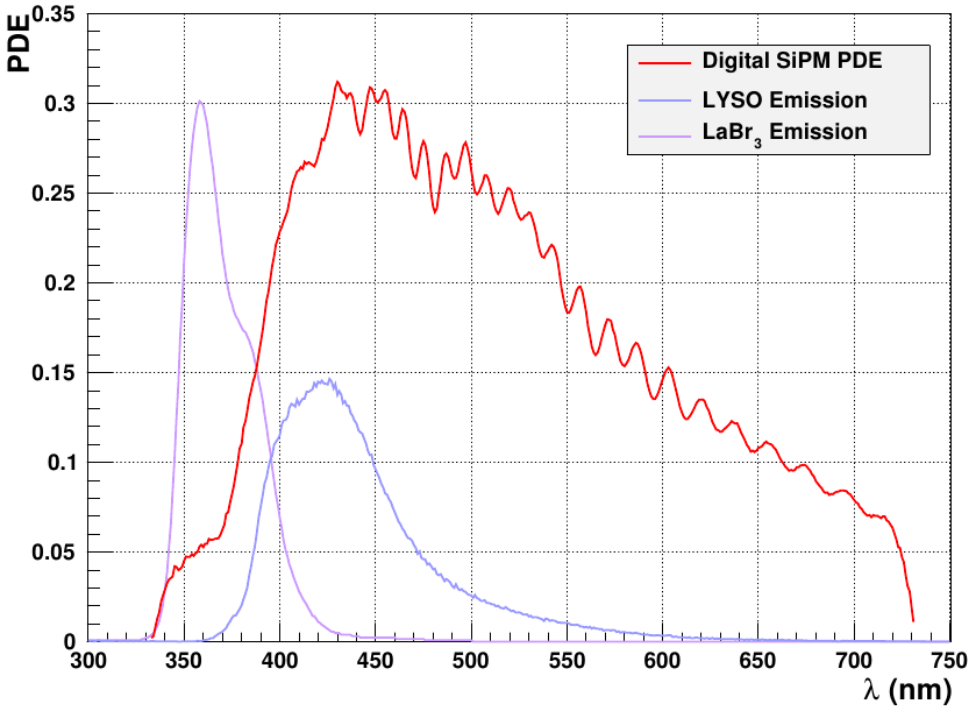
Digital SiPM – Photon Detection Efficiency



Effective PDE:

LYSO(Ce)	25.9%
CsI(Na)	23.7%
CsI(Tl)	20.5%
NaI(Tl)	24.2%
BGO	24.2%
$LaBr_3$(Ce)	9.6%

- Peak PDE >30% at 430nm and 3.3V excess voltage
- No anti-reflective coating used, optical coupling not optimized
- Needs independent verification

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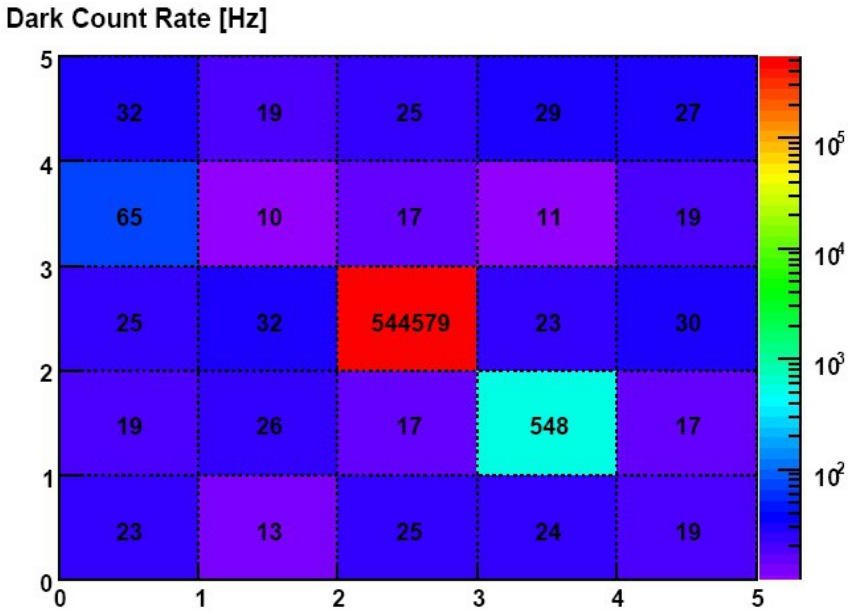
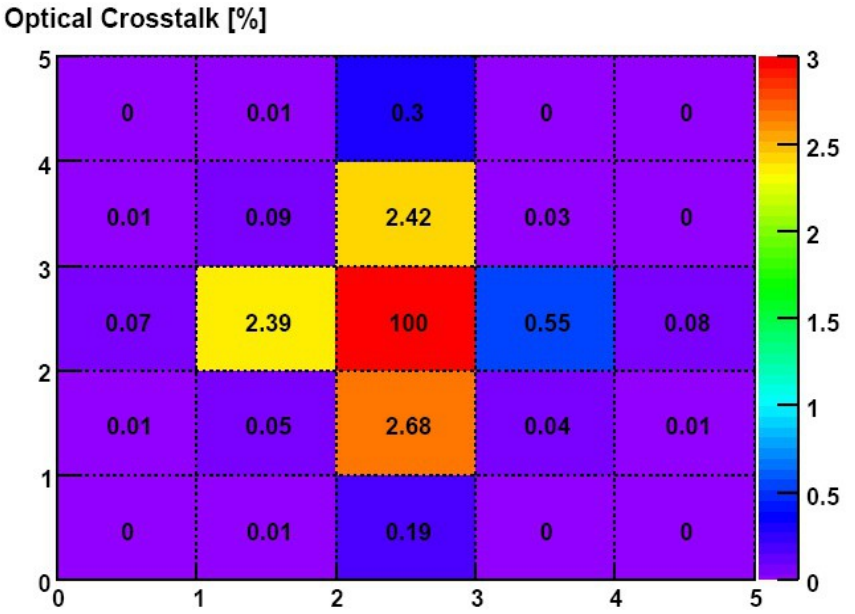
Digital SiPM – Optical Crosstalk





Direct measurement using one ‚bad' diode as light generator:

- Acquire dark count map around the light source for corrections
- Activate light source **and** test diode simultaneously:
  - Events with 1 photon are dark counts
  - Events with 2 photons are either randoms or optical crosstalk
- Use the dark count map to correct for randoms

Typical total optical crosstalk in a 5x5 neighborhood: 7% - 9%

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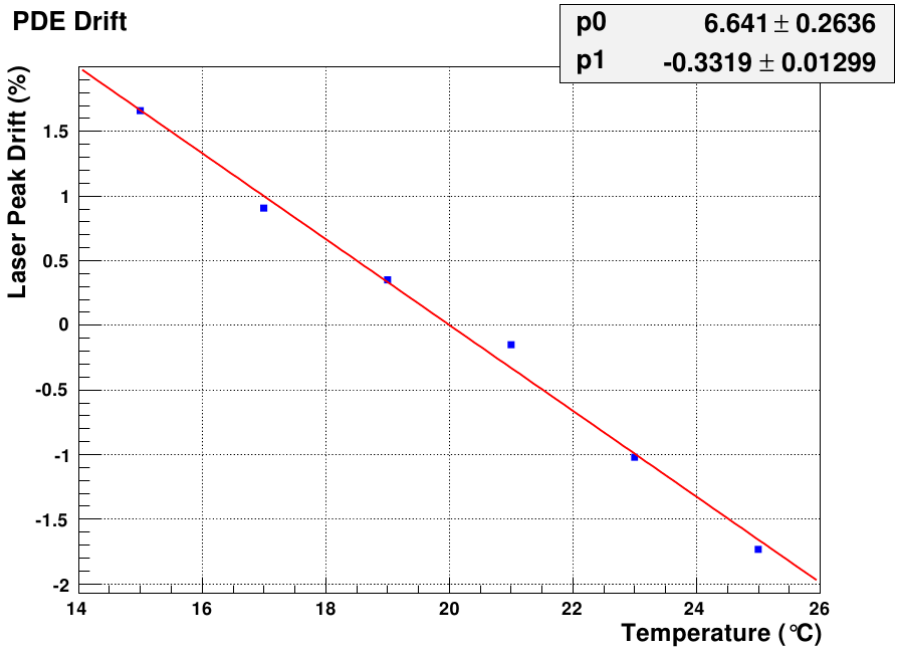
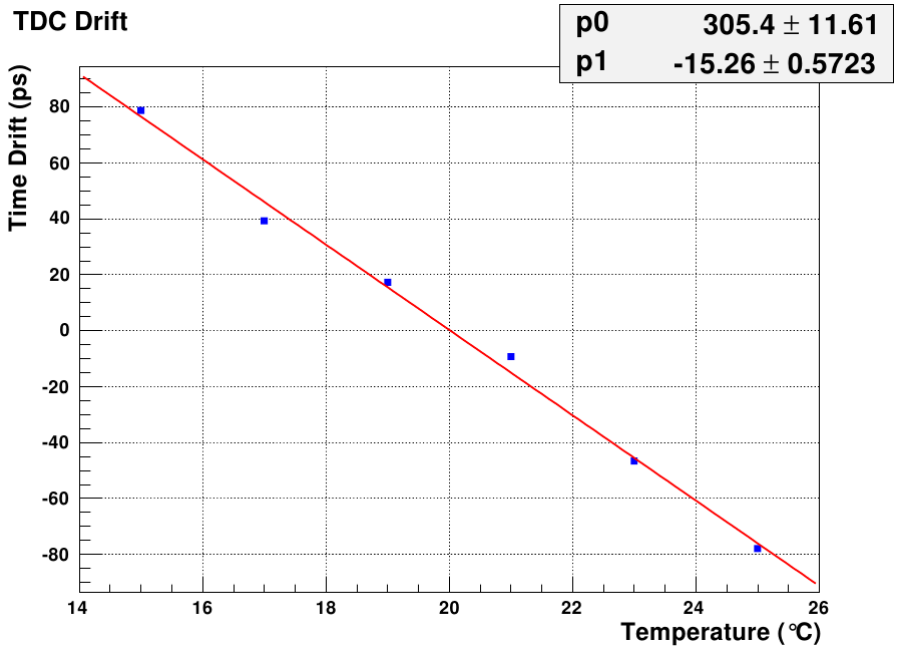
Digital SiPM – Temperature Sensitivity





ps-laser trigger, 2100 photons/pulse, 24ps FWHM timing resolution

- PDE drift: 0.33% K^{-1}
- TDC drift: 15.3ps K^{-1}
- PDE drift compensation by adapting the bias voltage
- TDC re-calibration using electrical trigger

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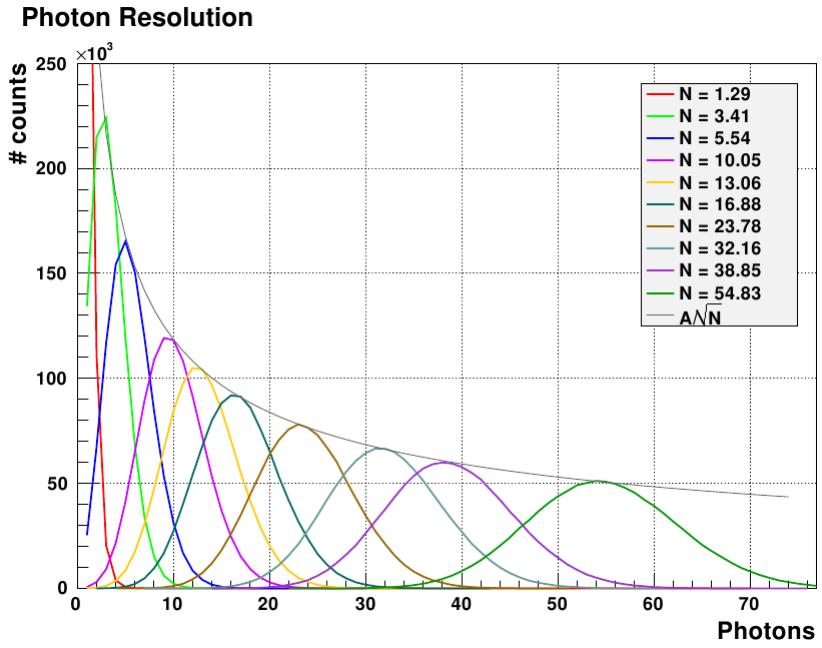
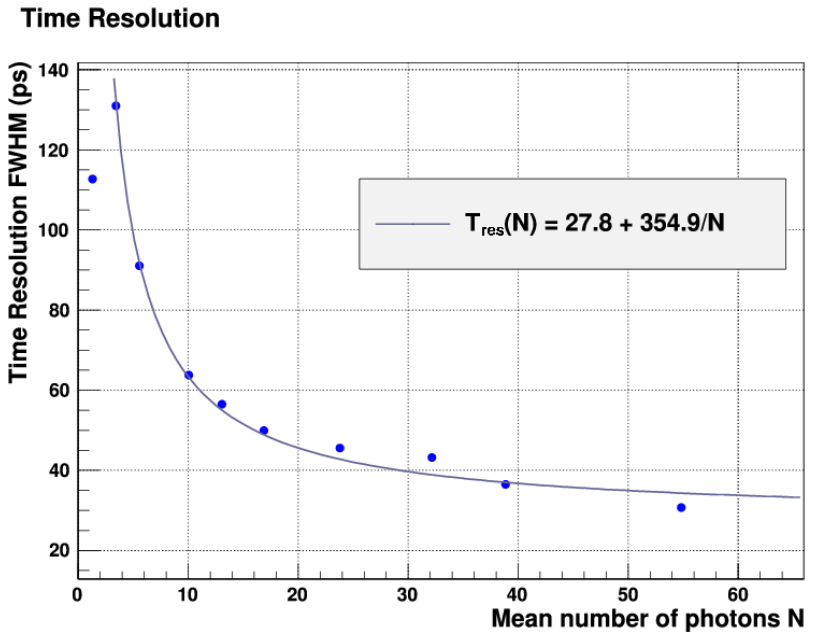
Digital SiPM – Photon And Time Resolution





- Sensor triggered by attenuated laser pulses at first photon level
- Laser pulse width: 36ps FWHM, λ = 410nm
- Contribution to time resolution (FWHM):

  SPAD: 54ps, trigger network: 110ps, TDC: 20ps

- Trigger network skew currently limits the timing resolution

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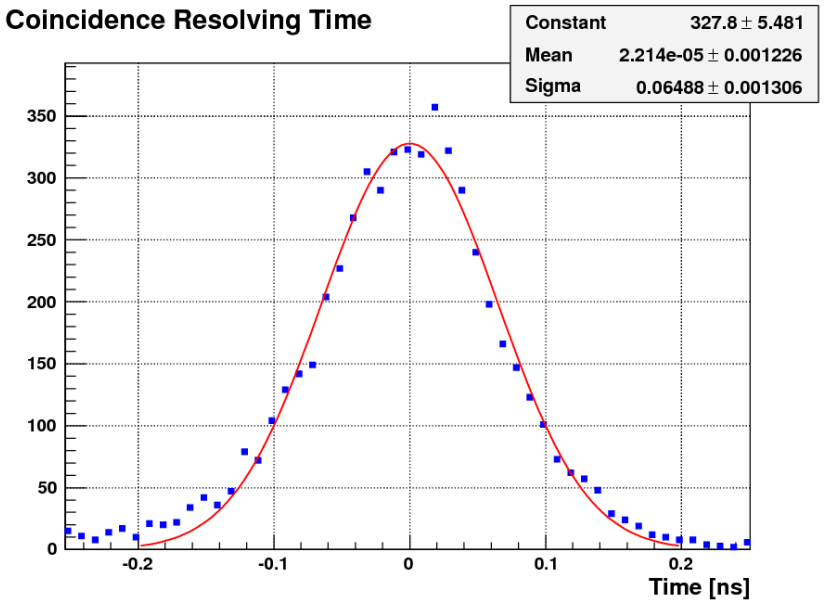
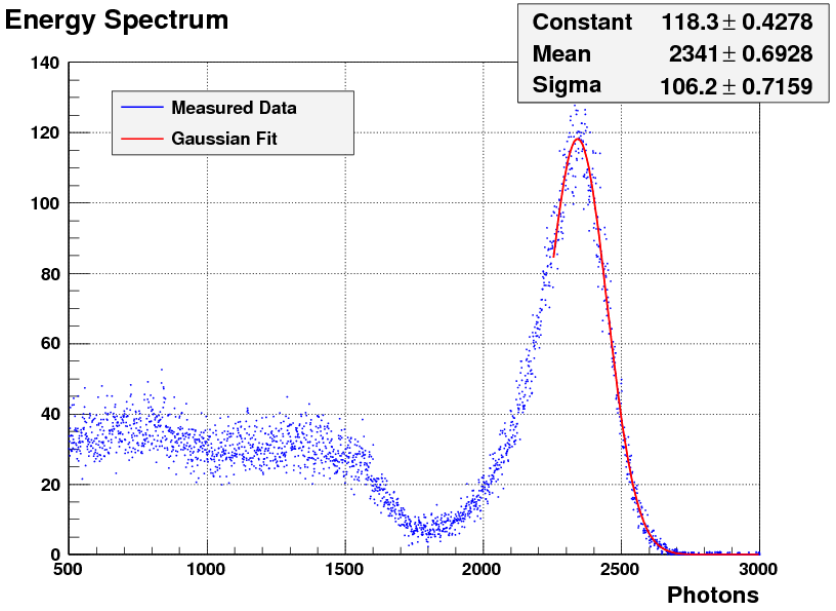
Digital SiPM – Scintillator Measurements



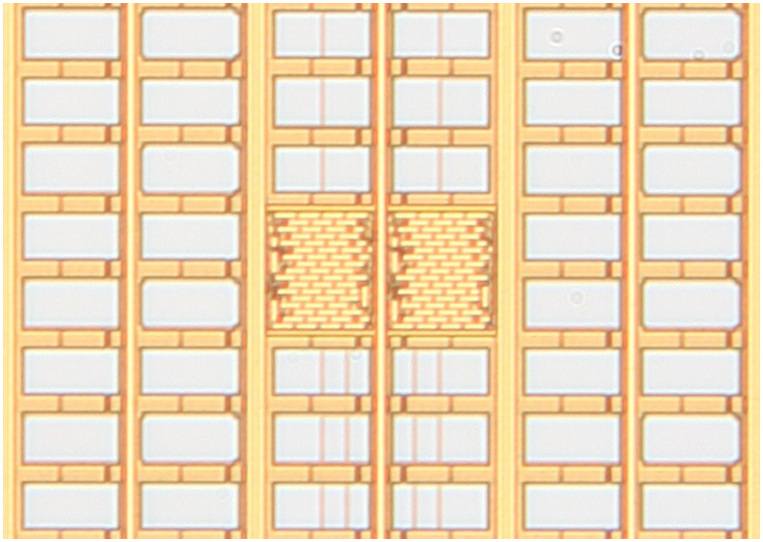


- 3 x 3 x 5 mm³ LYSO in coincidence, Na-22 source
- Time resolution in coincidence: **153ps** FWHM
- Energy resolution (excluding escape peak): **10.7**%
- Excess voltage 3.3V, 98.5% active cells
- Room temperature (31°C board temperature, not stabilized)

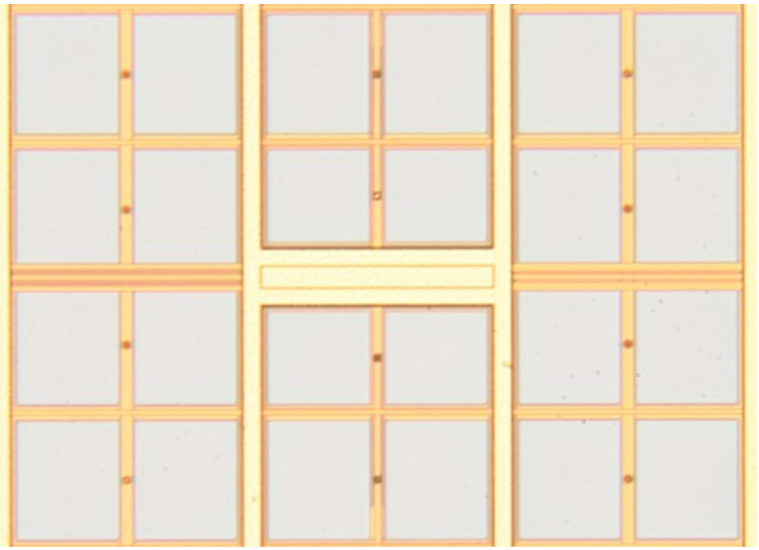
Digital SiPM – DLS 3200-22

New Experimental Design (DLS 3200-22):

- 3200 cells per pixel, 12800 cells per sensor
- 59.4µm x 64µm cell size, 78% area efficiency (incl. electronics)
- Based on (and compatible to) DLS 6400-22 sensor



DLS 6400-22



DLS 3200-22

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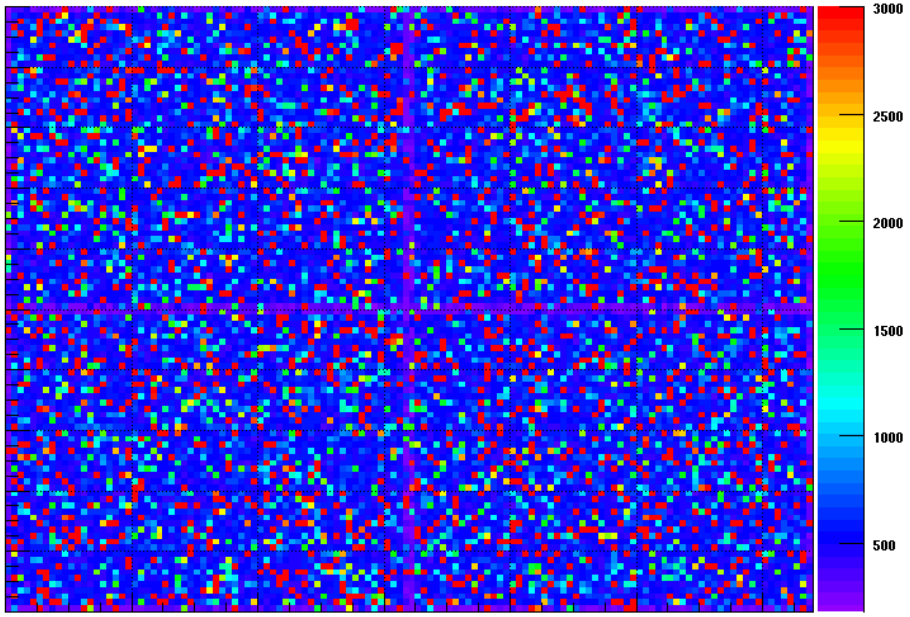
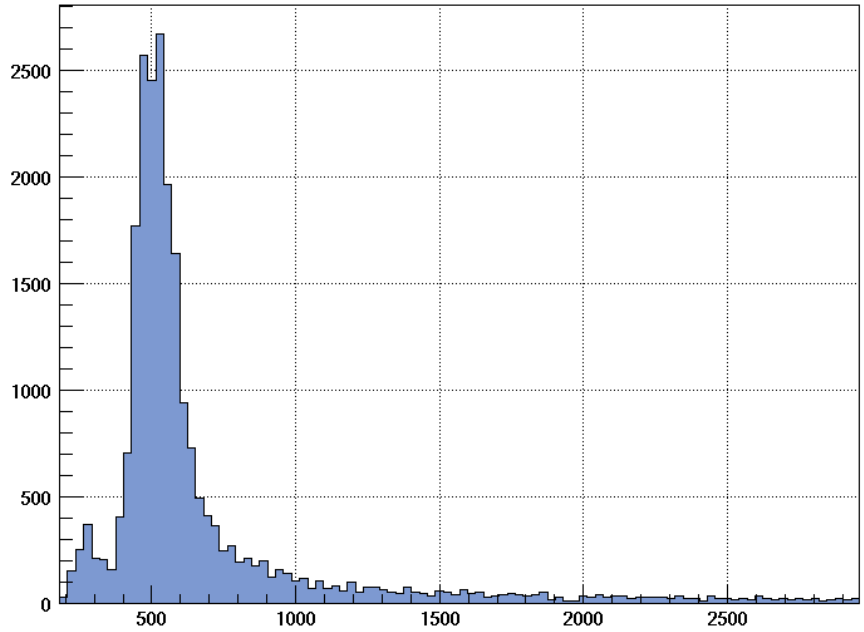
Digital SiPM – DLS 3200-22 Dark Count Rate





- Dark count rate at 20°C, 3.3V excess voltage
- Average dark count rate ~ 550cps per SPAD
- Scales with SPAD sensitive area (2954μm² vs. 783μm² in DLD8K)

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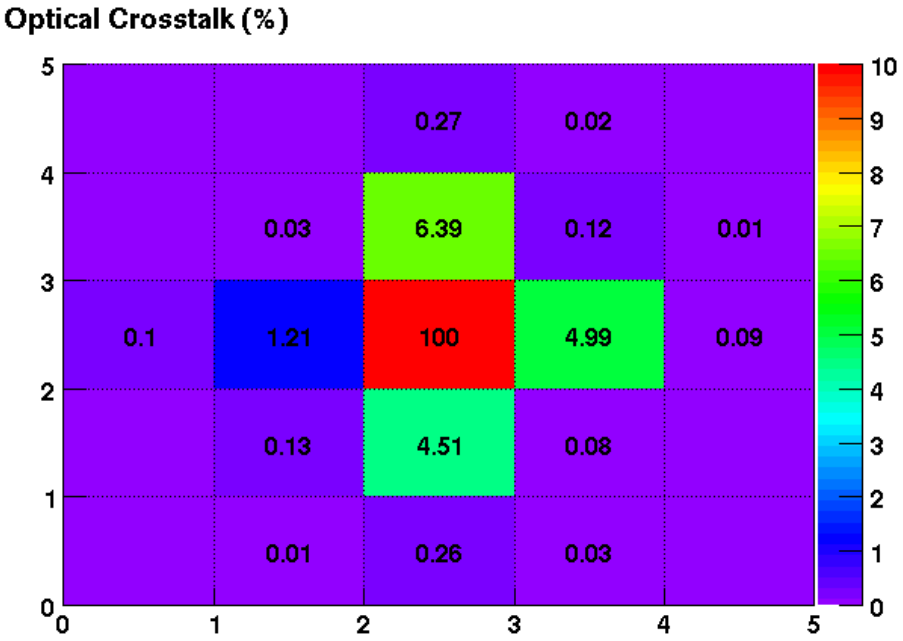
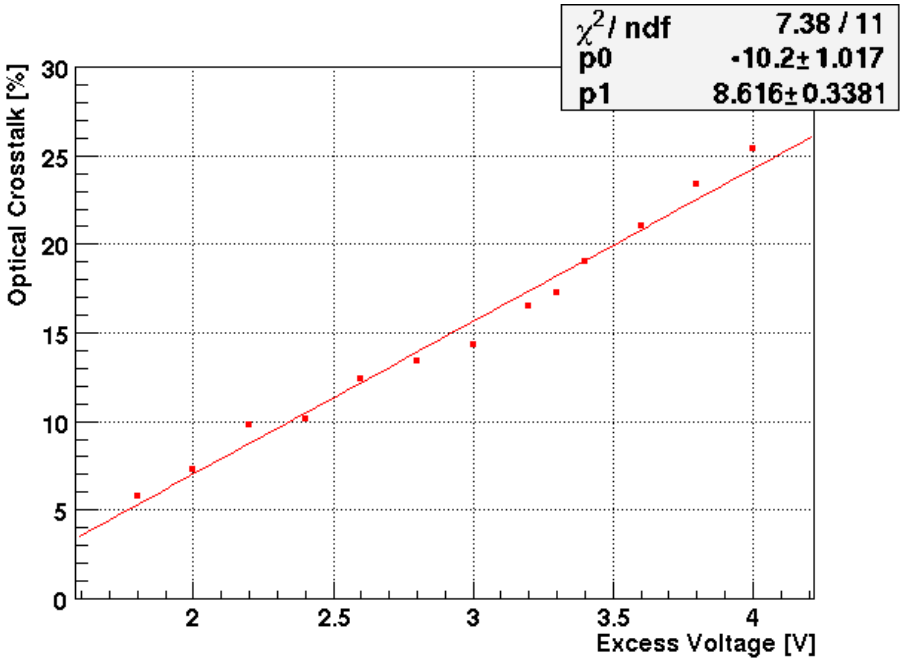
Digital SiPM – DLS 3200-22 Optical Crosstalk





- Optical crosstalk ~18% due to higher diode capacitance (factor ~2.8)
- Linear dependence on excess voltage (as expected)
- Has to be taken into account in saturation correction

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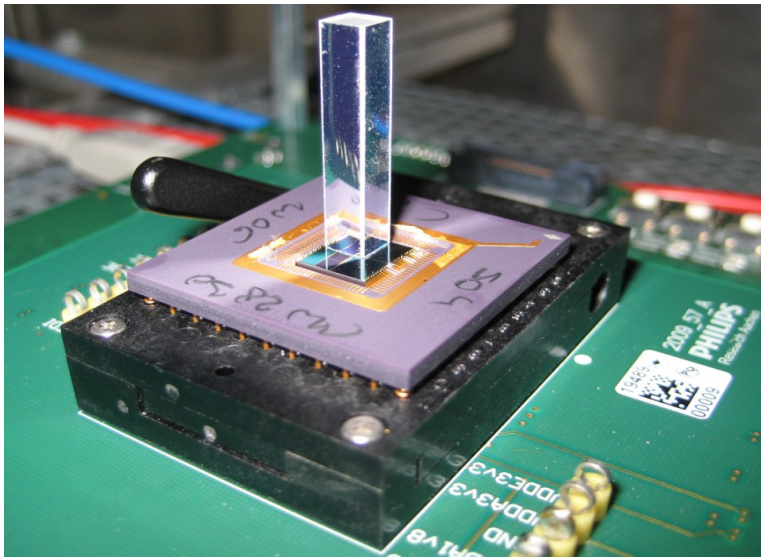
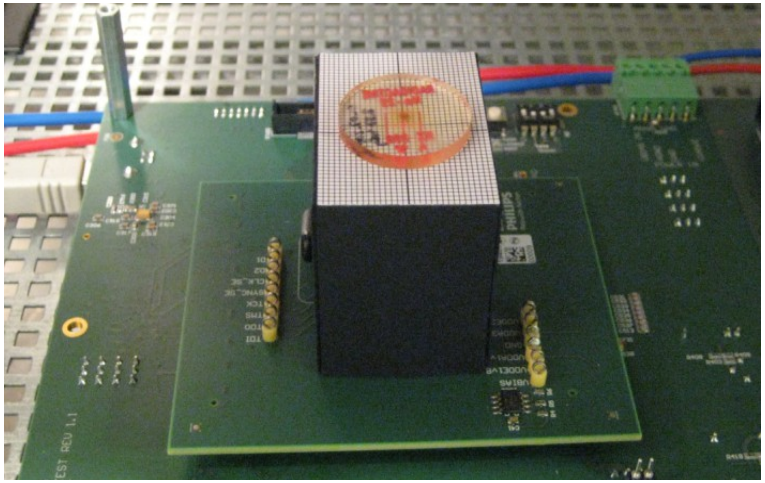
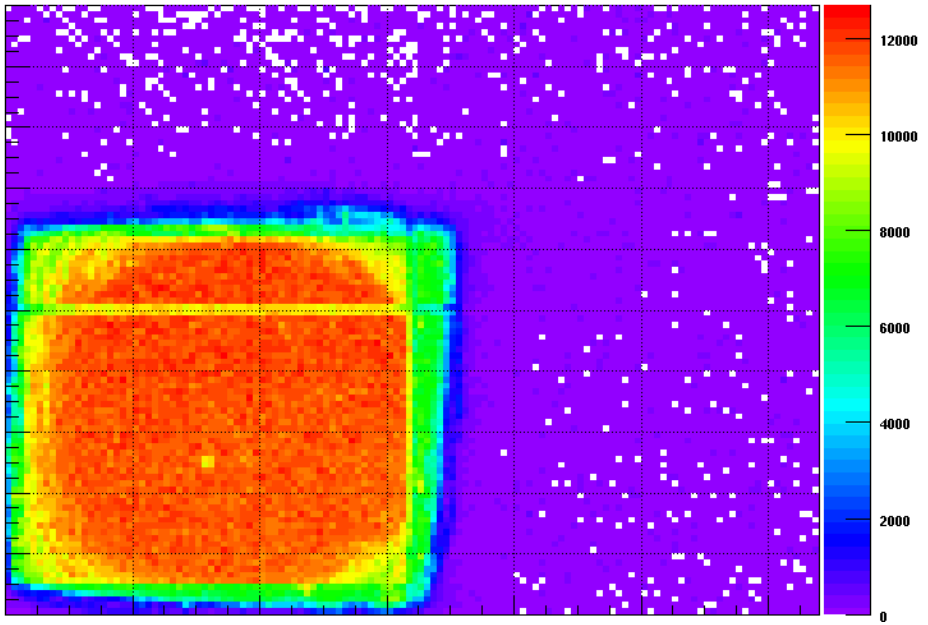
Digital SiPM – DLS 3200-22 Energy Resolution





- 4 x 4 x 22 mm³ LYSO crystal
- Vikuiti reflector
- Attached with Meltmount
- Na-22 source



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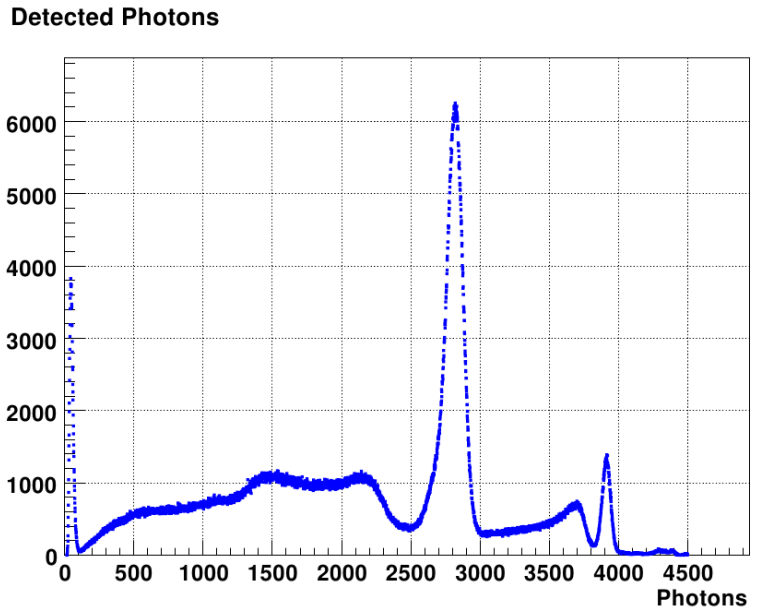
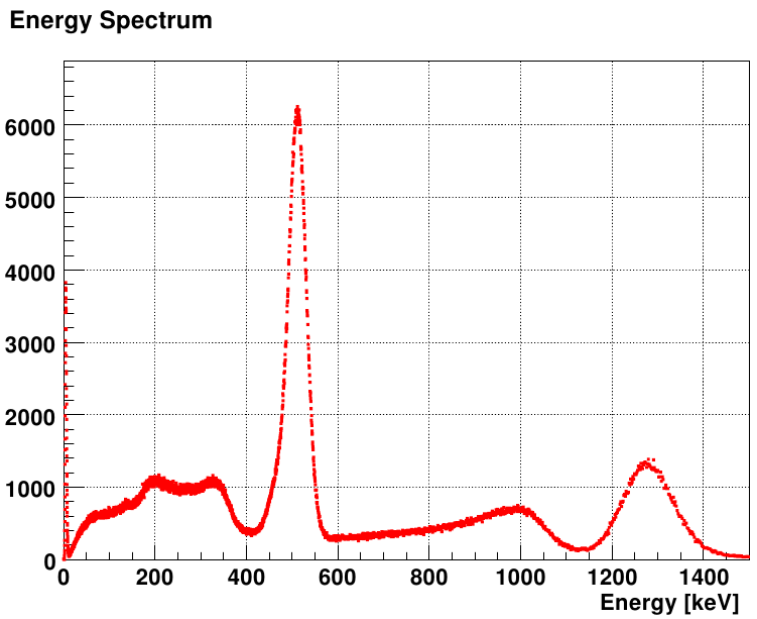
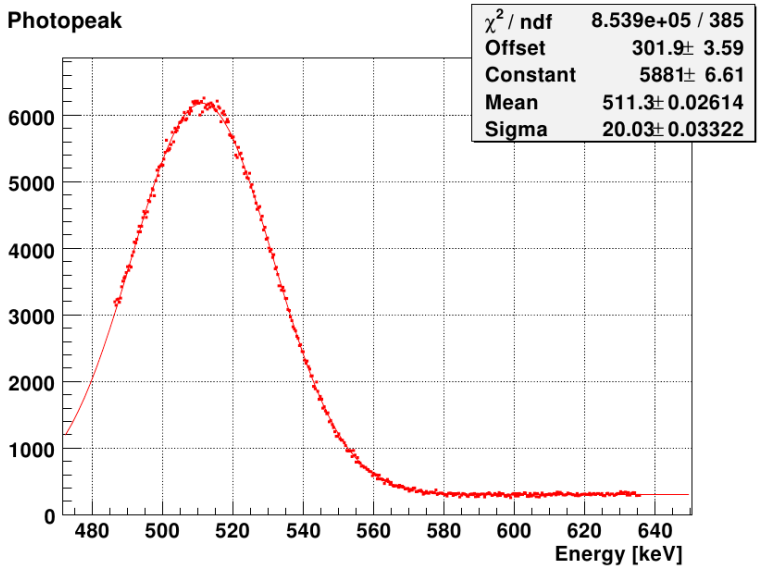
Digital SiPM – DLS 3200-22 Energy Resolution







- 3.3V excess voltage, 20°C
- 99% active cells
- Non-linearity correction
- Optical crosstalk included [Burr et al.]
- dE/E = 9.2%

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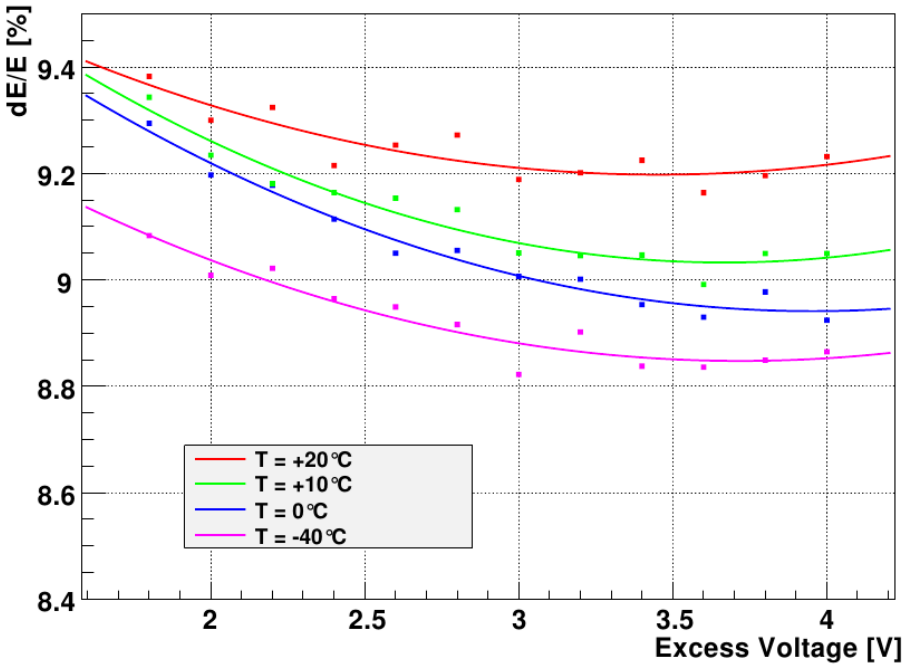
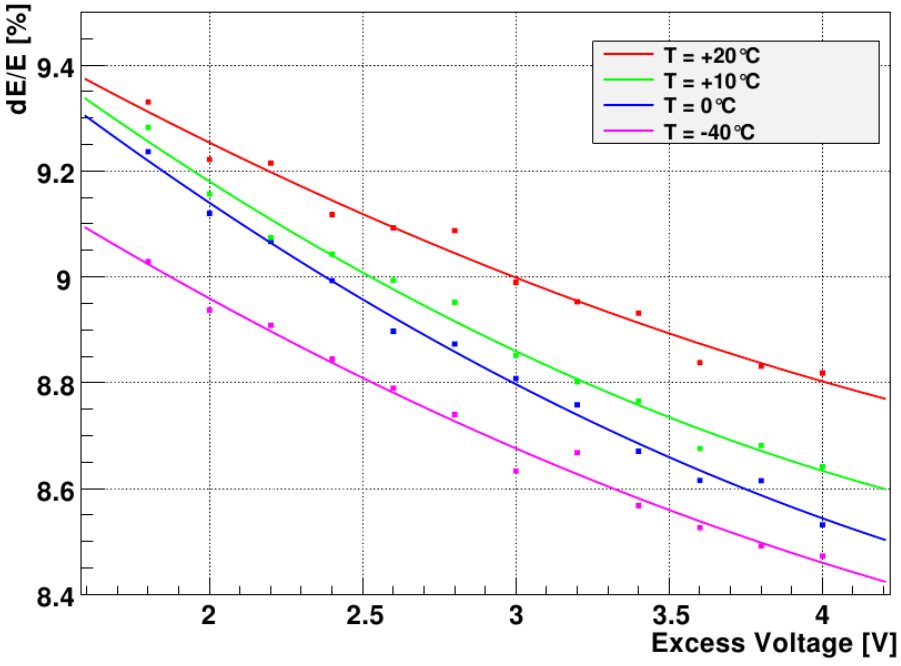
Digital SiPM – DLS 3200-22 Saturation Correction

Saturation correction including optical crosstalk model [Burr et al.,2007]:



Simple saturation correction neglecting optical crosstalk:



- Optical crosstalk seems to limit the energy resolution

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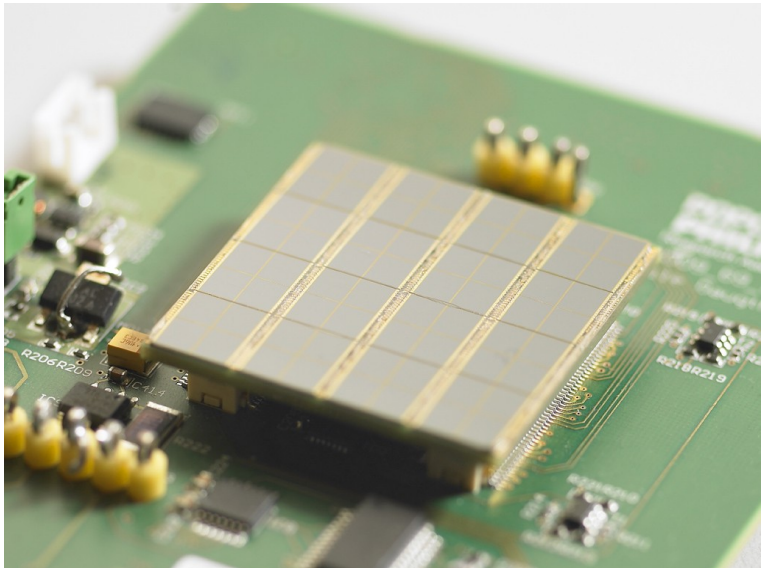
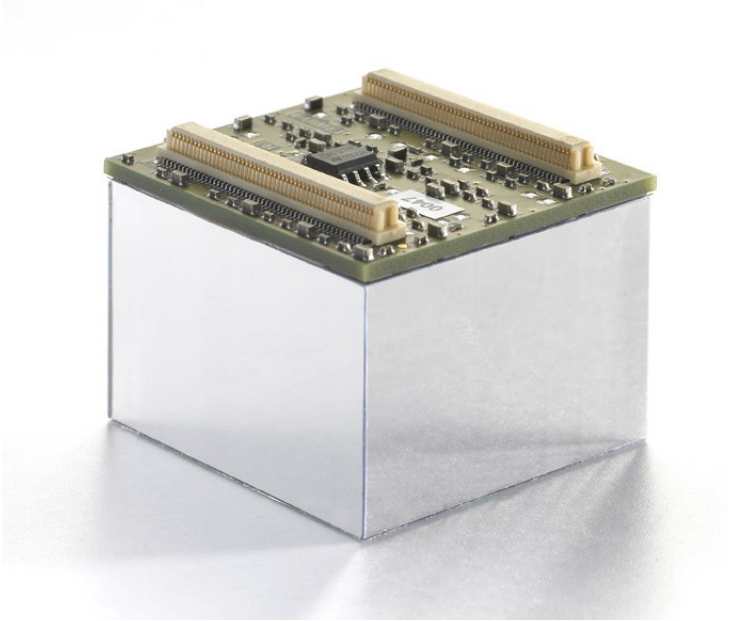
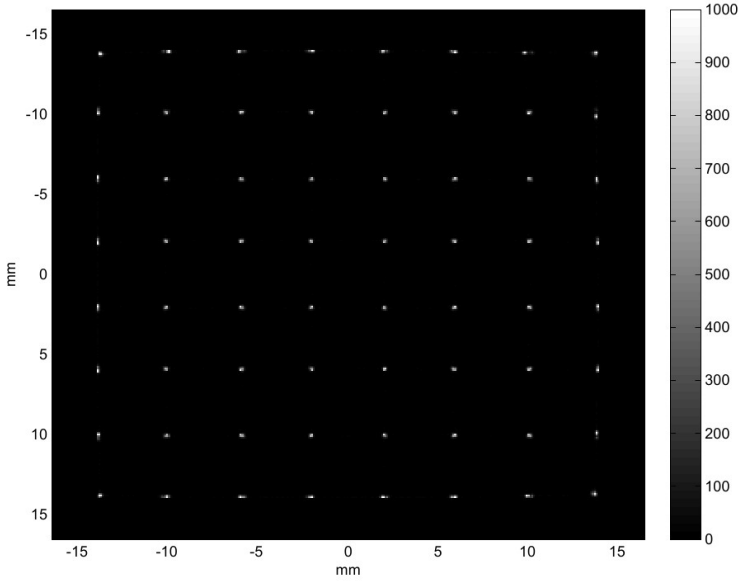
Digital SiPM – Tiles





- 4 x 4 sensor array
- 8 x 8 pixels
- 4-sides tileable
- see also Poster: PI-68



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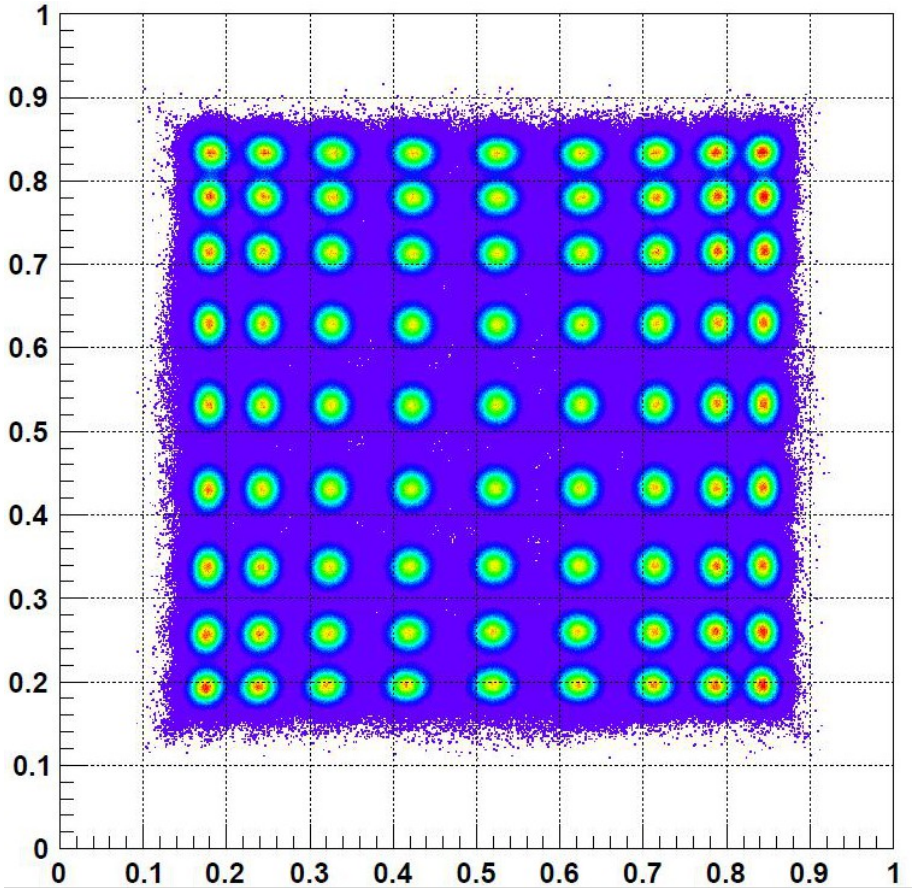
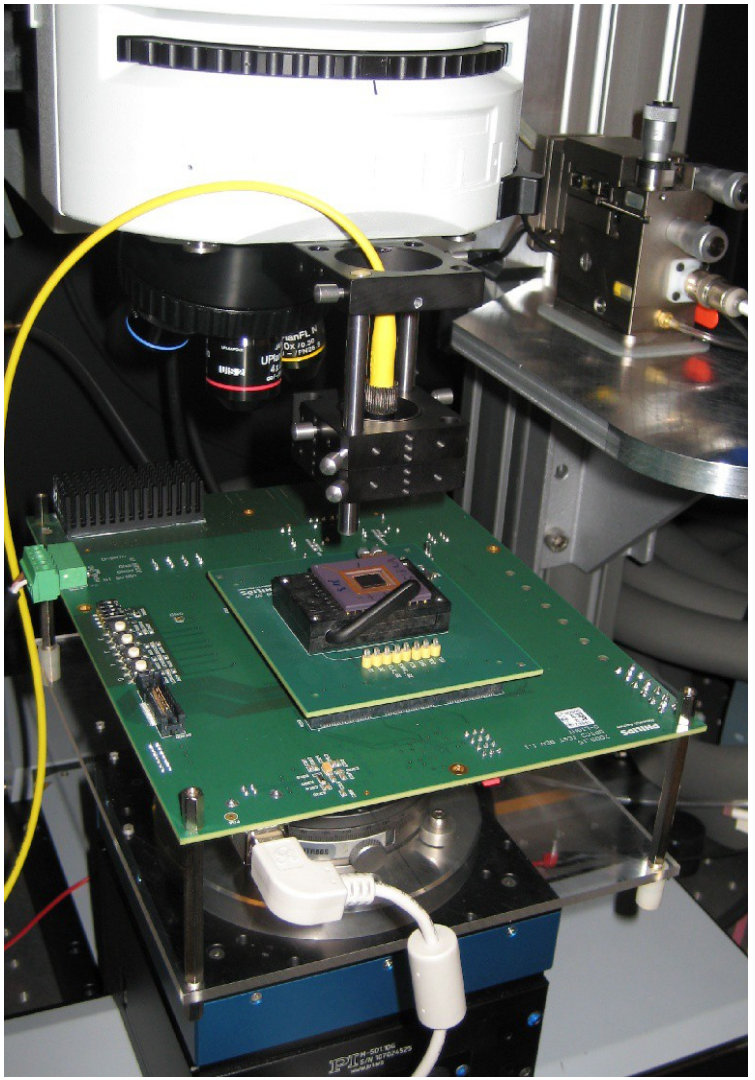
Digital SiPM – Small Crystal Identification

- Laser measurements on a 0.5mm grid
- Best case (no scatter, no light guide)
- ~1600 photons per laser pulse





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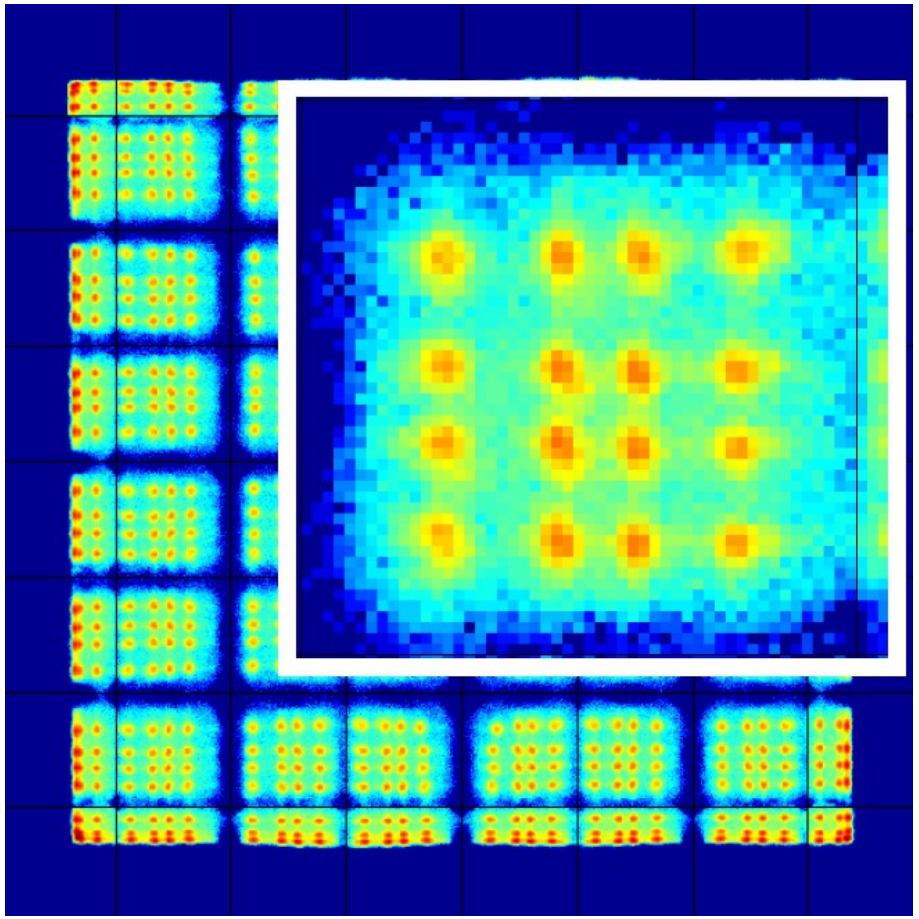
Digital SiPM – Small Crystal Identification

- Array of 30 x 30 LYSO crystals
- Crystal size: 1 x 1 x 10mm³
- Coupled via light guide to one digital SiPM tile (4 x 4 dies)
- Data plotted in log scale
- Strong floodmap compression close to tile edge due to missing neighbor tiles



P. Düppenbecker, Philips Research

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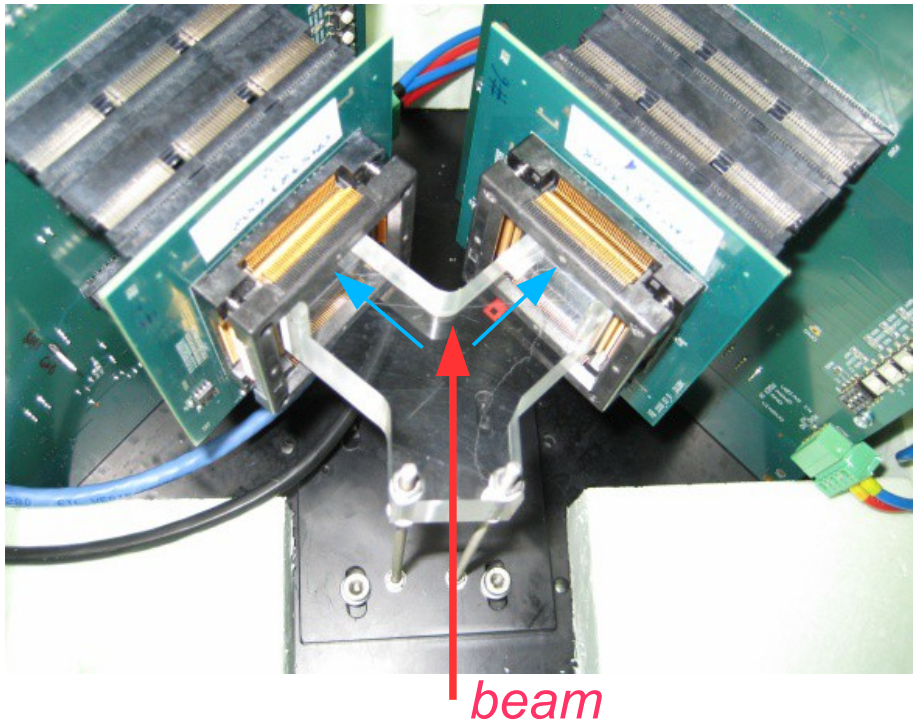
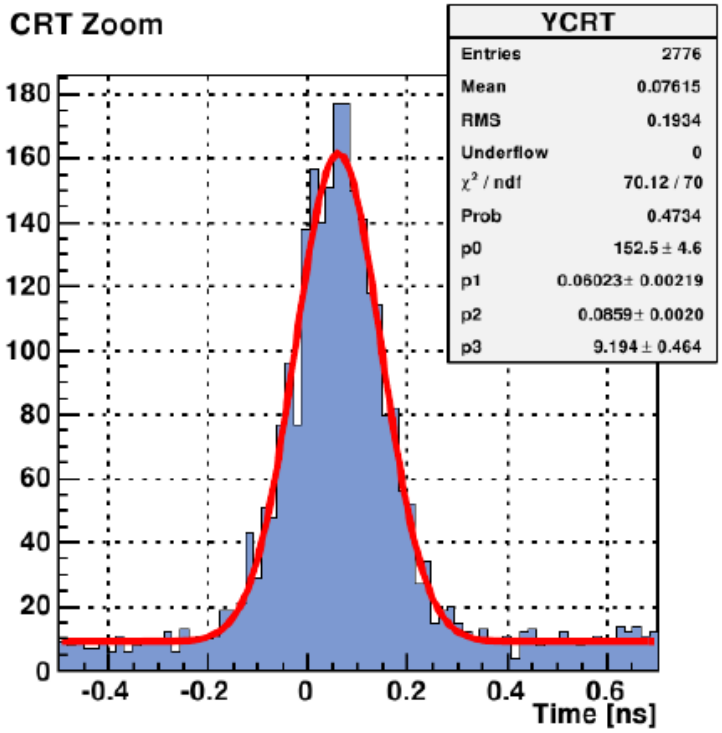
Digital SiPM – Čerenkov Light Detection





- PMMA radiator coupled via air gap to two dSiPMs (DLD8K) in coincidence
- Box isolated and temperature-controlled with a TEC to 2 – 3°C
- Cooperation between Giessen University (Prof. Düren) and Philips DPC
- First measurements at CERN SPS: **σ = 60.7ps**

Summary

- Digital SiPM implemented in a high-volume CMOS process
- Configurable architecture, individual control of each SPAD
- Two-sides tileable sensor design
- Tiles of 4 x 4 sensors developed to simplify system integration
  (see also poster presentation PI-68 by C. Degenhardt)
- New design with improved fill factor of 78% currently being tested

The author would like to thank Dr. Hein Valk of NXP Semiconductors for his support and excellent cooperation during the process development

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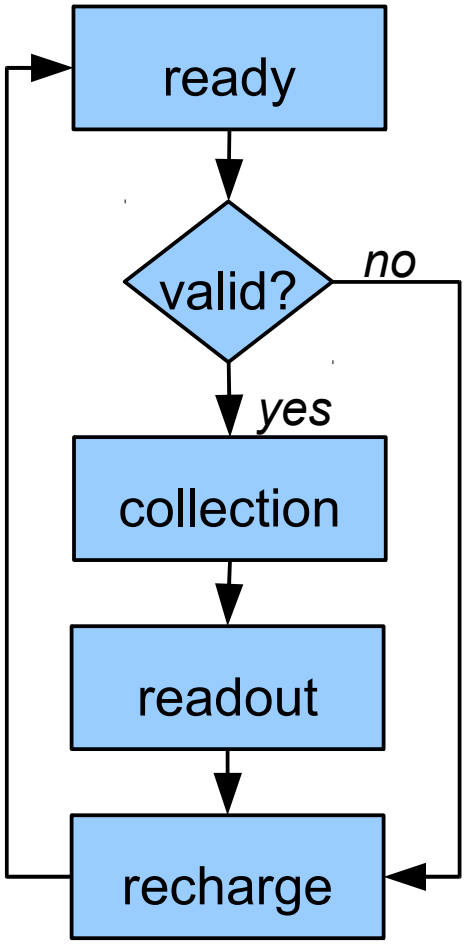
Digital SiPM – State Machine



5ns – 80ns

0ns – 20µs

680ns

10ns – 40ns

- *200MHz (5ns) system clock*
- *Variable light collection time up to 20µs*
- *20ns min. dark count recovery*
- *dark counts => sensor dead-time*
- *data output parallel to the acquisition of the next event (no dead time)*
- *Trigger at 1, ≥2, ≥3 and ≥4 photons*
- *Validate at ≥4 ... ≥64 photons (possible to bypass event validation completely)*

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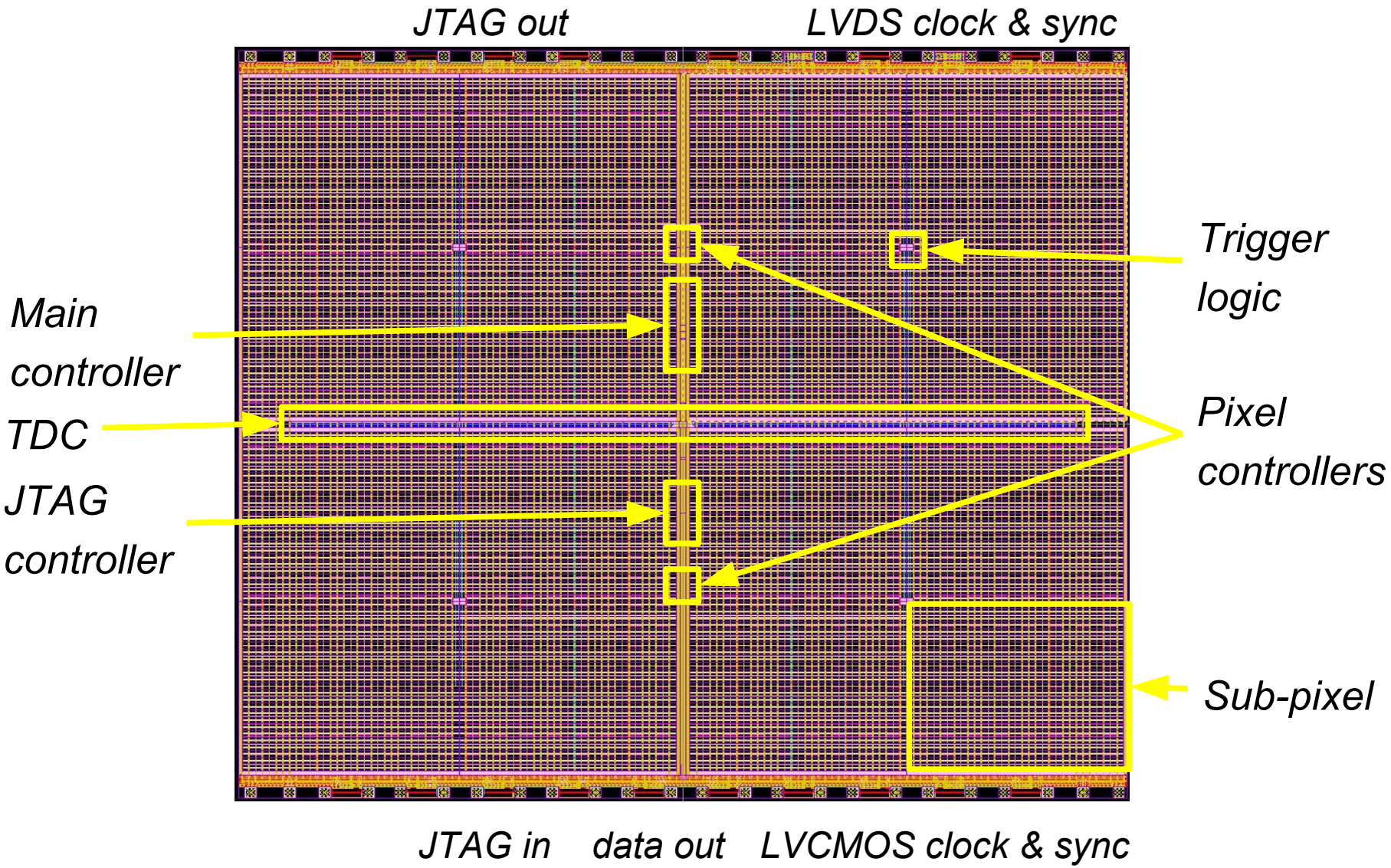
Digital SiPM – Sensor Architecture



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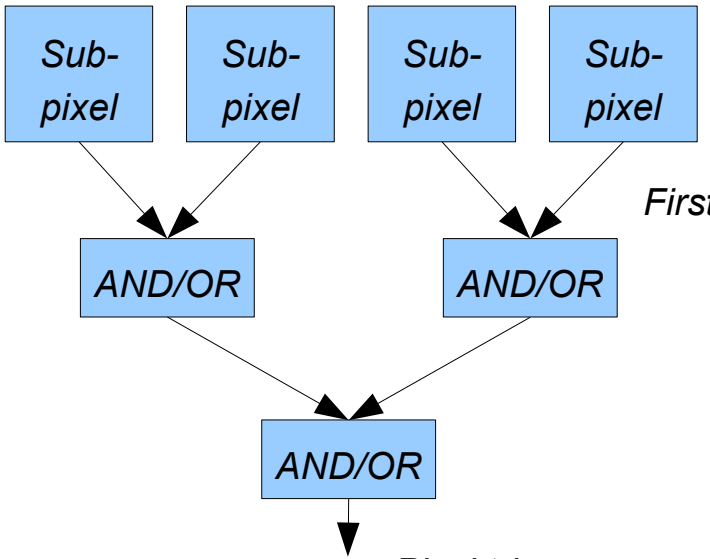
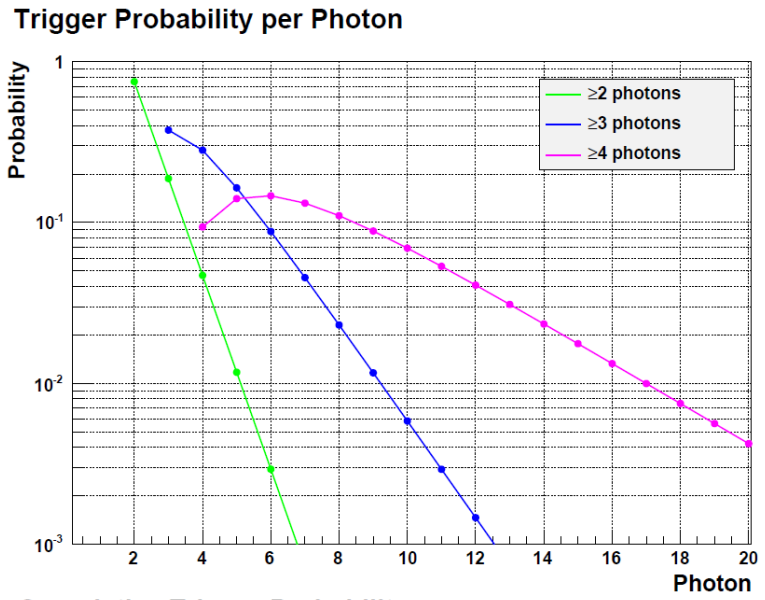
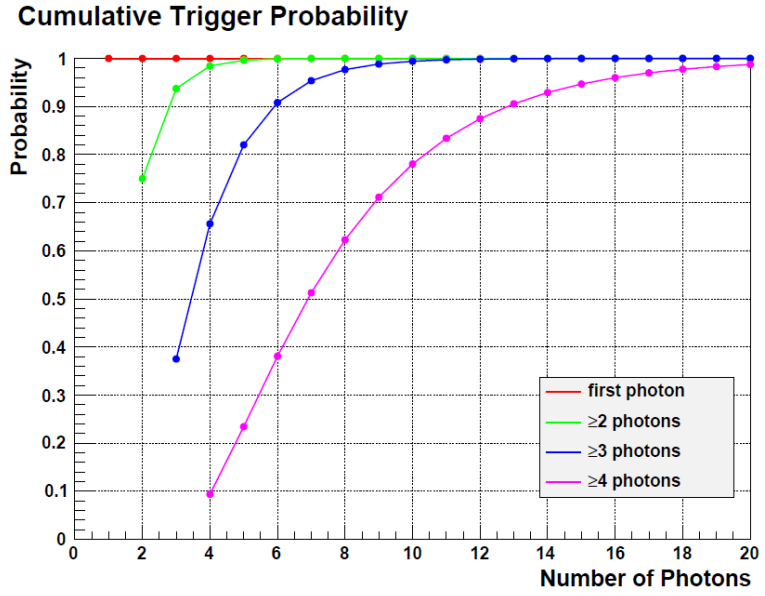
Digital SiPM – Trigger Logic







- *Each sub-pixel triggers at first photon*
- *Sub-pixel trigger can be OR-ed or AND-ed to generate probabilistic trigger thresholds*
- *Higher trigger threshold decreases system dead-time at high dark count rates at the cost of time resolution*

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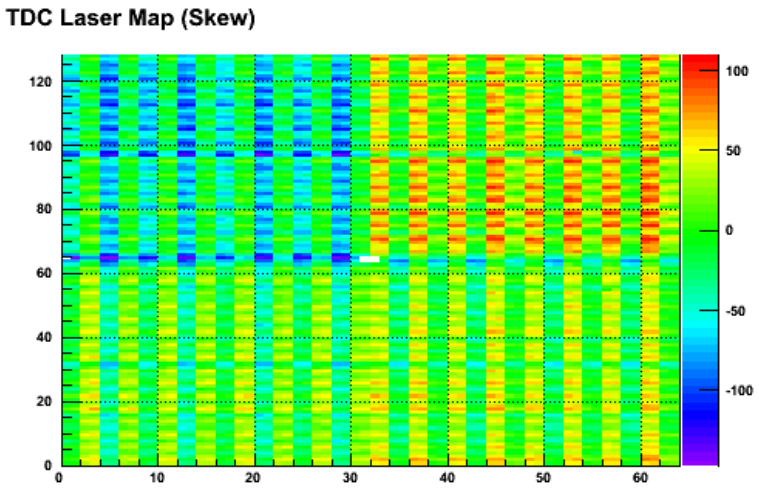
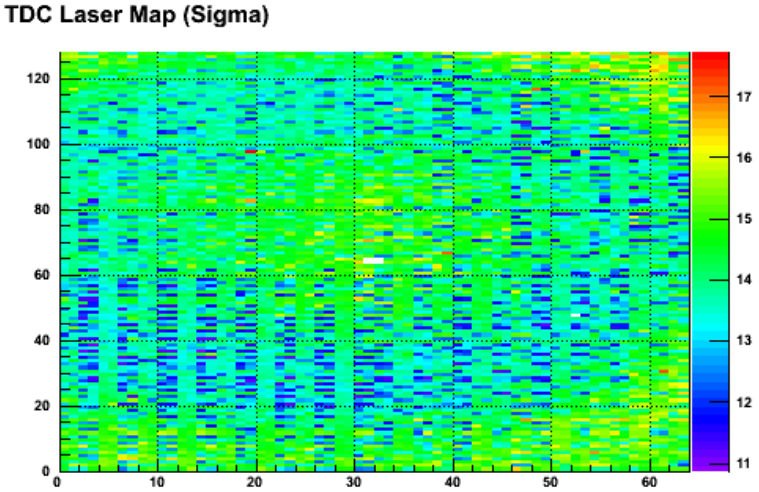
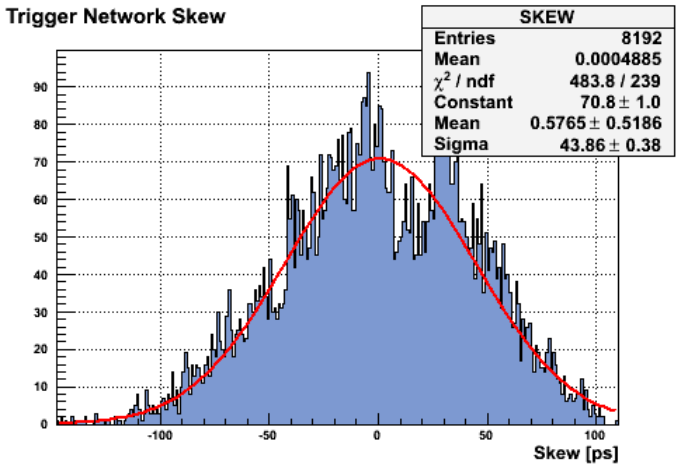
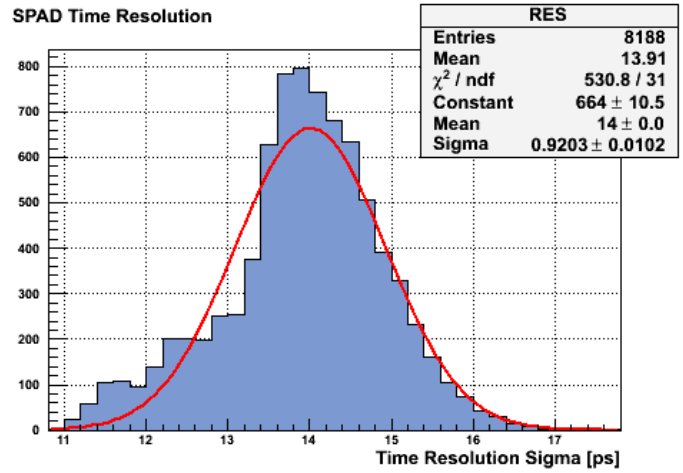
Digital SiPM – Trigger Network Skew





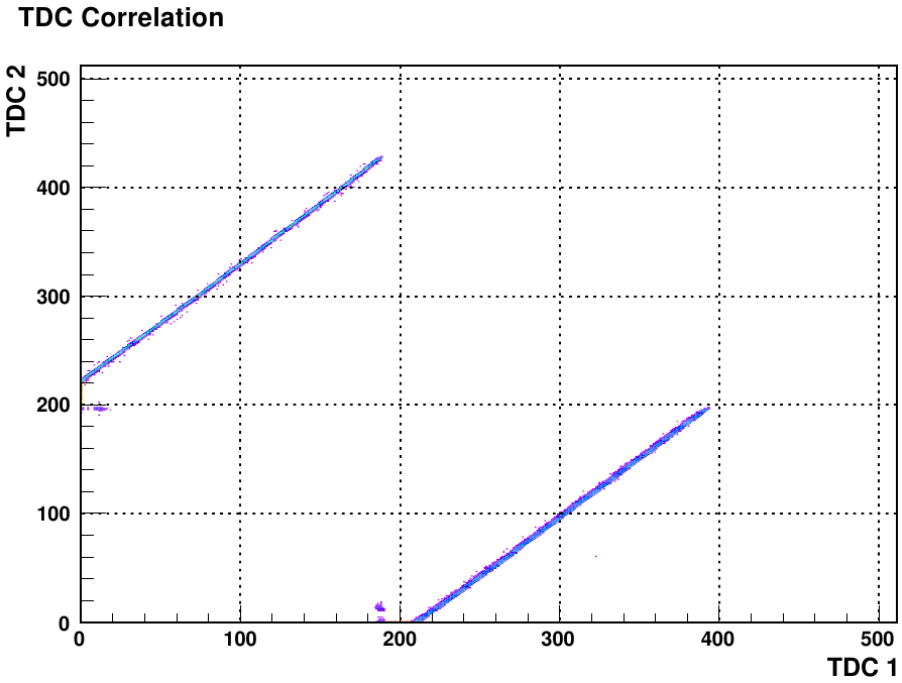


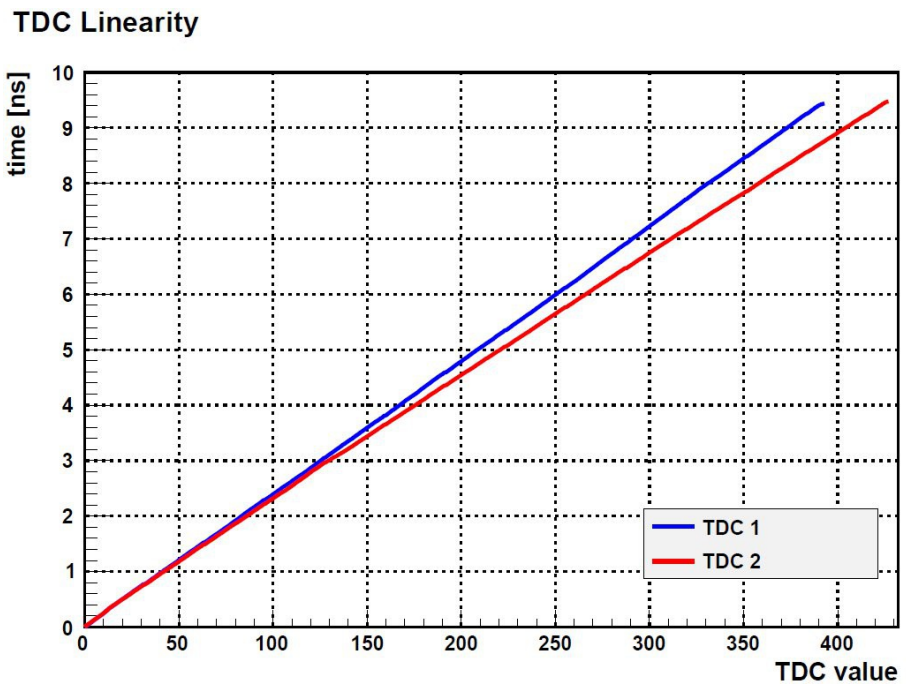


- Diodes activated one-by-one and triggered by a divergent ps-laser pulse.
- Many photons per diode&pulse → negligible avalanche spread uncertainty.
- Laser trigger&pulse spread and TDC resolutions are included in the final σ_T

PHILIPS

Digital SiPM – Time-to-Digital Converter

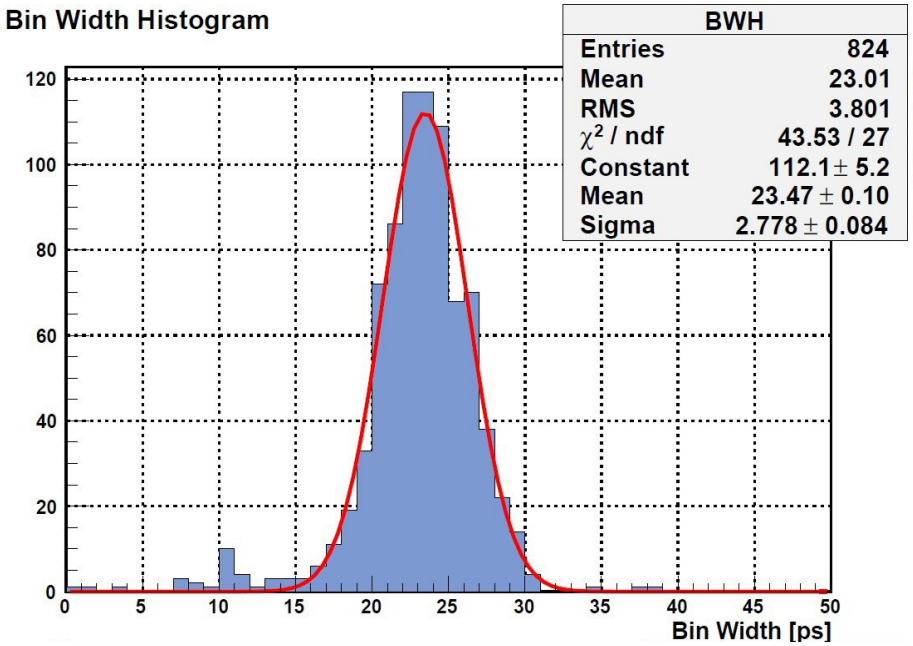


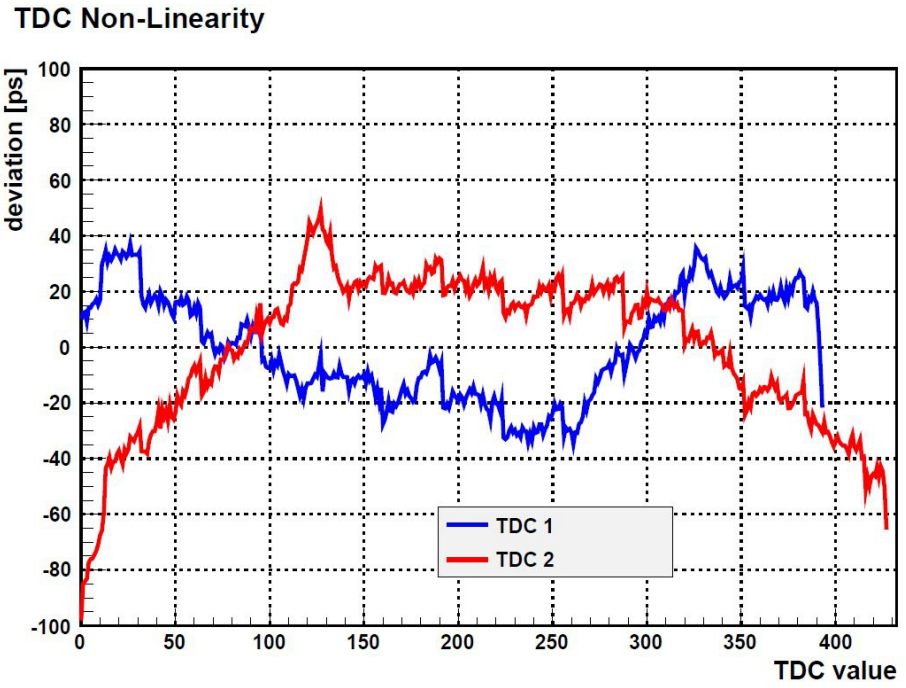


- Two identical 9 bit TDCs running with 180° phase-shifted clocks
- 100MHz reference clock generated from 200MHz system clock
- Each TDC has ~0.5ns wide 'blind spot' close to clock edge → bin 0
- Two-phase clock guarantees at least one valid TDC value for any event
- For ~90% of the events, both TDC values can be used to increase accuracy
- TDC calibration using dark counts or randomly distributed events

PHILIPS

Digital SiPM – Time-to-Digital Converter

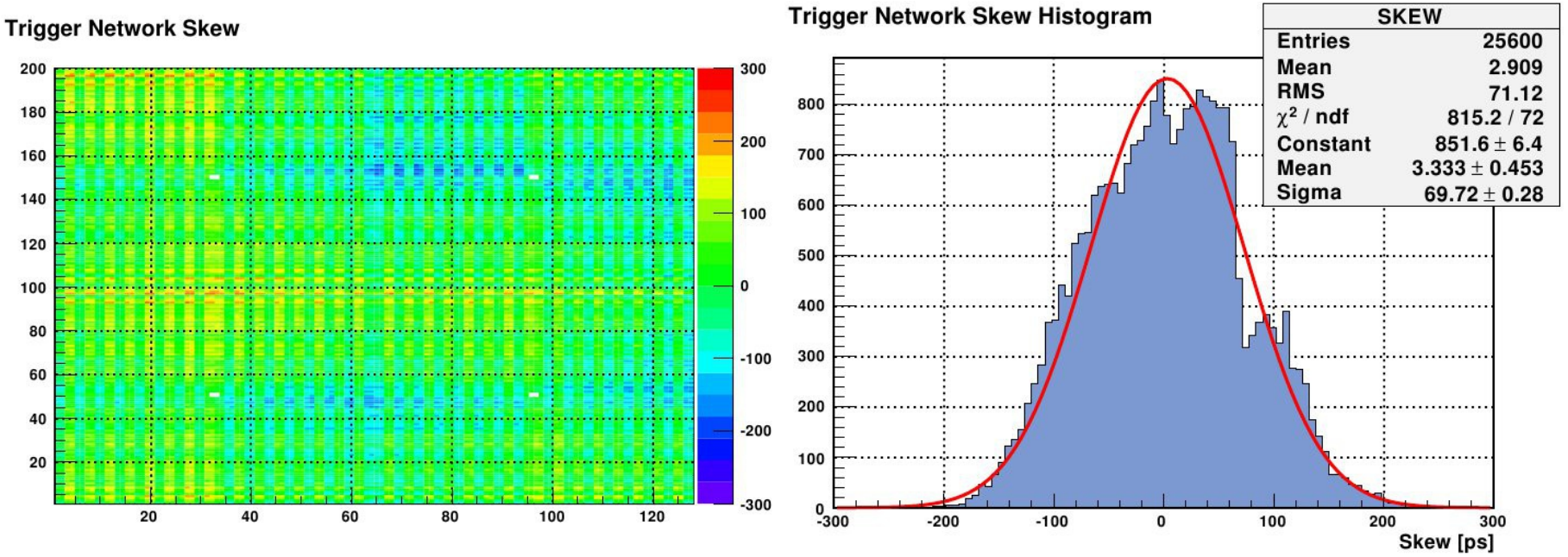




- Average TDC bin width 23 ± 2.8ps
- Non-linearity corrected by look-up tables inside the readout FPGA
- Online correction for TDC drift due to temperature and voltage variation
- Periodic TDC calibration test using external (SYNC) signal

PHILIPS

Digital SiPM – Trigger Network Skew



- Chip illuminated by divergent picosecond laser beam
- Laser trigger synchronized to the reference clock
- All diodes measured sequentially
- 10000 events captured and time stamp histogram fitted with a Gaussian
- Gaussian mean → delay of the selected trigger path
- Average trigger network delay subtracted from the data